UTC UNISONIC TECHNOLOGIES CO., LTD

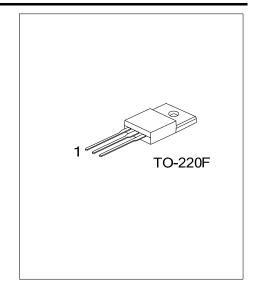
9N50 **Preliminary Power MOSFET**

N-CHANNEL 9A, 500V **POWER MOSFET**

DESCRIPTION

The UTC 9N50 is an N-channel mode power MOSFET using UTC's advanced technology to provide customers planar stripe and DMOS technology. This technology allows a minimum on-state resistance, superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

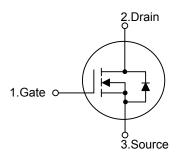
The UTC 9N50 is generally applied in high efficiency switch mode power supplies, active power factor correction and electronic lamp ballasts based on half bridge topology.



FEATURES

- * $R_{DS(ON)}$ =0.85 Ω @ V_{GS} =10V
- * High Switching Speed
- * Improved dv/dt Capability
- * 100% Avalanche Tested

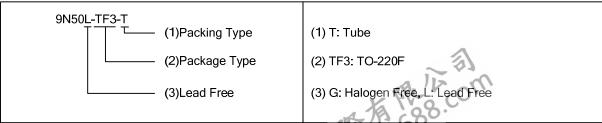
SYMBOL



ORDERING INFORMATION

	Ordering Number		Deelvere	Pin Assignment			Dooking
ĺ	Lead Free	Halogen Free	Package	1	2	3	Packing
ĺ	9N50L-TF3-T	9N50G-TF3-T	TO-220F	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source



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■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise noted)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	500	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous (T _C =25°C)	I _D	9 (Note 5)	Α	
Jiain Guirent	Pulsed (Note 2)	I _{DM}	36 (Note 5)	Α	
Avalanche Current (Note 2)		I _{AR}	9	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	360	mJ	
	Repetitive (Note 4)	E _{AR}	13.5	mJ	
Peak Diode Recovery	dv/dt (Note 4)	dv/dt	4.5	V/ns	
Power Dissipation		В	44	W	
Derate above 25°C		- P _D	0.35	W/°C	
Junction Temperature		TJ	+150	°C	
Storage Temperature	·	T _{STG} -55~+150		ů	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 8mH, I_{AS} = 9A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 4. $I_{SD} \le 9A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- 5. Drain current limited by maximum junction temperature

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	θ_{JC}	2.86	°C/W	



■ **ELECTRICAL CHARACTERISTICS** (T_C=25°C, unless otherwise noted)

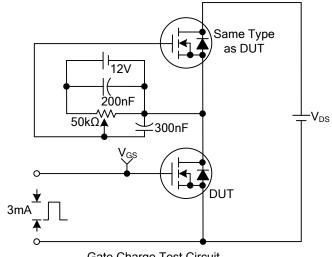
PARAMETER	SYMBOL	TEST CONDITIONS MI		TYP	MAX	UNIT		
OFF CHARACTERISTICS			•					
Drain-Source Breakdown Voltage	BV _{DSS}	I_D =250 μ A, V_{GS} =0 V	500			V		
Drain Course Leakage Current	I _{DSS}	V _{DS} =500V, V _{GS} =0V			1			
Drain-Source Leakage Current		V _{DS} =400V, T _C =125°C			10	μΑ		
Gate- Source Leakage Current Forward]	V_{GS} =+30V, V_{DS} =0V			+100	nΑ		
Reverse	I _{GSS}	V_{GS} =-30V, V_{DS} =0V			-100	nΑ		
ON CHARACTERISTICS								
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$			4.0	V		
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =4.5A		0.7	0.85	Ω		
DYNAMIC PARAMETERS								
Input Capacitance	C _{ISS}	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		790	1030	pF		
Output Capacitance	Coss			130	170	pF		
Reverse Transfer Capacitance	C_{RSS}			24	30	pF		
SWITCHING PARAMETERS								
Total Gate Charge	Q_G	V _{GS} =10V, V _{DS} =400V, I _D =9A -(Note 1, 2)		28	35	nC		
Gate to Source Charge	Q_GS			4		nC		
Gate to Drain Charge	Q_GD			15		nC		
Turn-ON Delay Time	t _{D(ON)}	V _{DD} =250V, I _D =9A, R _G =25Ω (Note 1, 2)		18	45	ns		
Rise Time	t _R			65	140	ns		
Turn-OFF Delay Time	t _{D(OFF)}			93	195	ns		
Fall-Time	t _F			64	125	ns		
SOURCE- DRAIN DIODE RATINGS AND	CHARACTERI	STICS						
Maximum Body-Diode Continuous Current	Is				9	Α		
Maximum Body-Diode Pulsed Current	I _{SM}				36	Α		
Drain-Source Diode Forward Voltage	V_{SD}	I _S =9A, V _{GS} =0V			1.4	V		
Body Diode Reverse Recovery Time	t _{rr}	I _S =9A, V _{GS} =0V, dI _F /dt=100A/μs		335		ns		
Body Diode Reverse Recovery Charge	Q_{RR}	(Note 1)		2.95		μC		

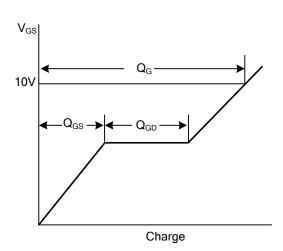
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%



^{2.} Essentially independent of operating temperature

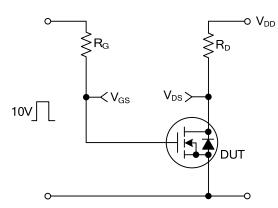
TEST CIRCUITS AND WAVEFORMS

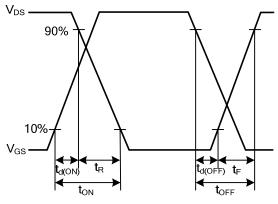




Gate Charge Test Circuit

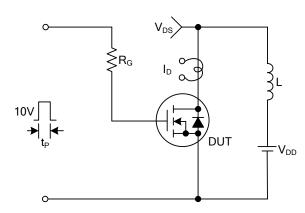
Gate Charge Waveforms

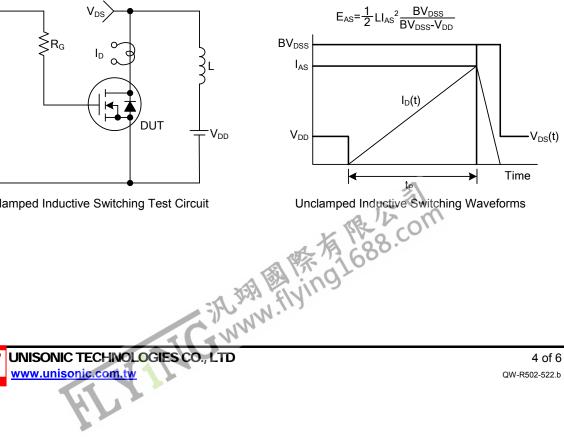




Resistive Switching Test Circuit

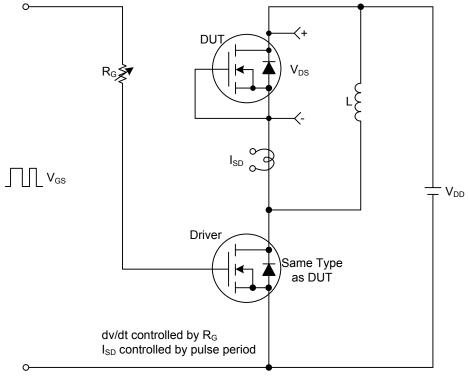
Resistive Switching Waveforms



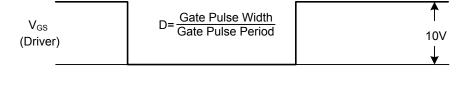


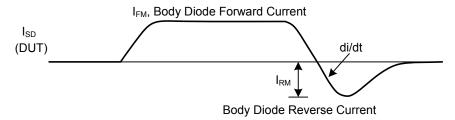
Unclamped Inductive Switching Test Circuit

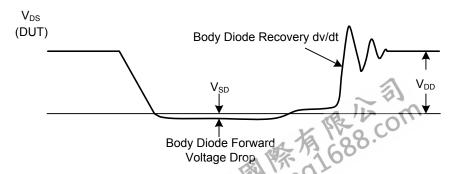
■ TEST CIRCUITS AND WAVEFORMS(Cont.)



Peak Diode Recovery dv/dt Test Circuit & Waveforms







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